

Notice of References Cited

Application/Control No.

10/046,742

Applicant(s)/Patent Under

Reexamination

NAMBA ET AL.

Examiner

Yvette C. Thornton

Art Unit

1752

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	JP 10-048826 URANO et al., abstract; POLYMER COMPOSITION AND RESIST MATERIAL CONTAINING THE SAME
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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